CIVA UT Training

CIVA 2015 Training – UT



서울시 강남구 학동로 101길 26, 308호

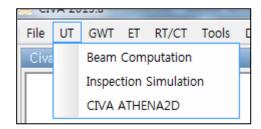
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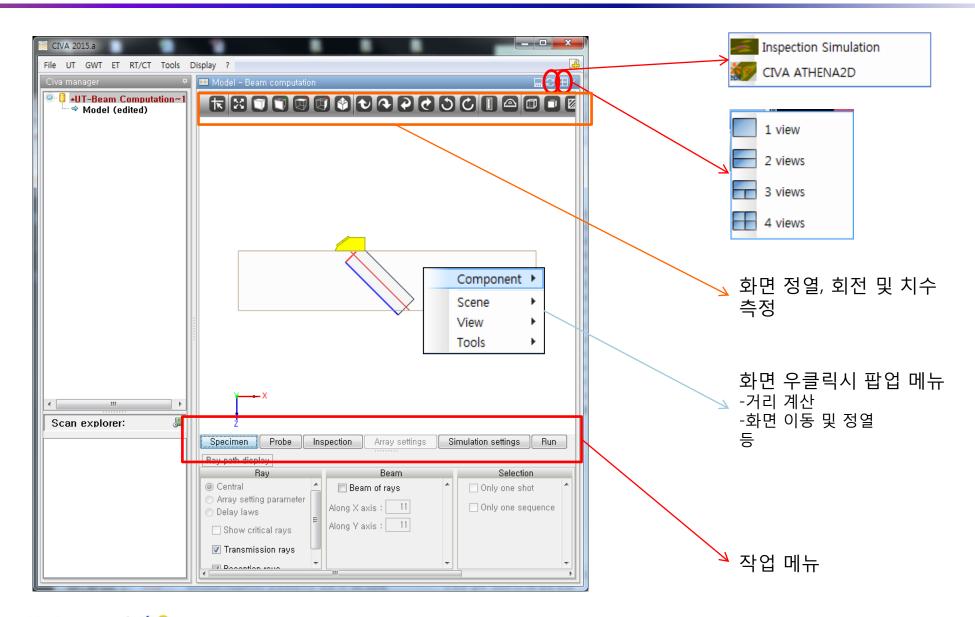
♦UT – main menu

- Beam Computation : 탐촉자를 이용한 시편에서의 초음파 계산
- Inspection Simulation : 결함 또는 시편에 대한 에코계산
- CIVA ATHENA2D : 유한요소 계산을 필요로 하는 복잡한 상호 작용과 시편에서의 에코 계산



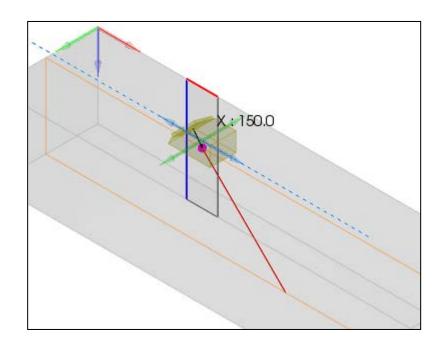


❖MENU 및 화면 안내





❖마우스 이용 방법



-화면에서의 마우스는

1. 좌 클릭: 화면 이동

2. 우 클릭 : 화면 확대(아래), 축소(위)

3. 휠 버튼 클릭: 회전

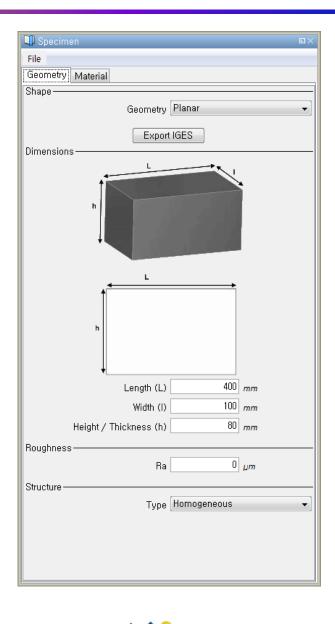
-Probe 및 Specimen 선택

Probe 및 Specimen을 마우스 좌버튼 더블 클릭시 활성화 되며 동시에 x,y,z 축의 화살표가 생성이 됩니다.

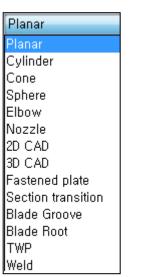
생성된 화살표를 이용하여 각 축을 따라 이동 시킬 수 있습니다.

이러한 방법으로 화면에 표현되는 형태의 위치를 변경할 수 있습니다.

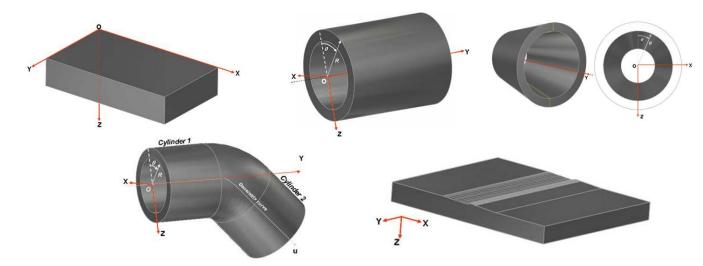
❖Specimen 설정



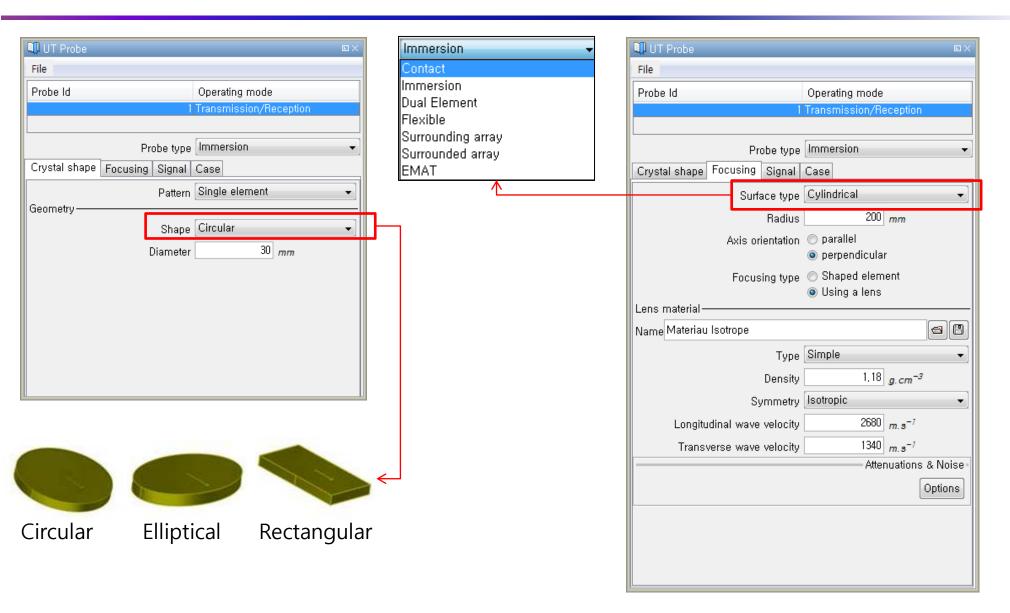
보유 형상 : 보유 물성 :



Fluid Simple Homogeneous multiple-ply composite Single ply composite Granular composite Coarse Grained Polycrystalline Fluid

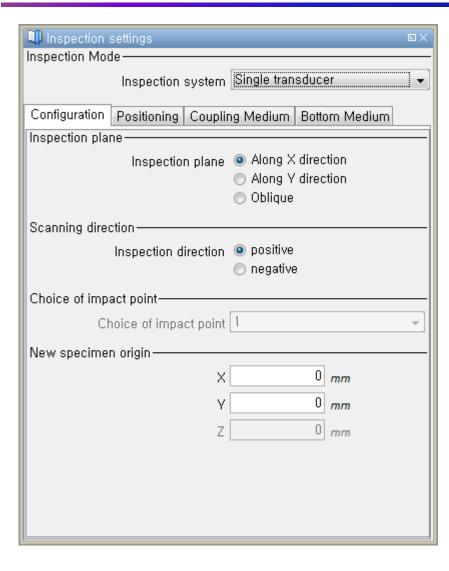


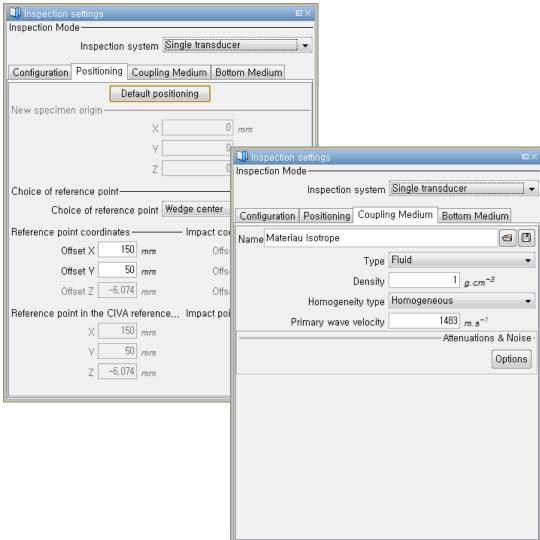






❖Inspection settings







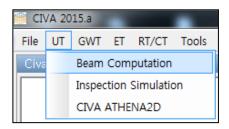
❖Example 1 – Immersion Testing

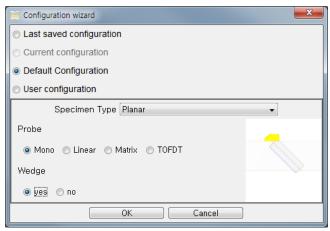
- 1. L0 inspection with a non-focused transducer
- 2. L0 inspection with a spherically focused transducer
- 3. L60 inspection



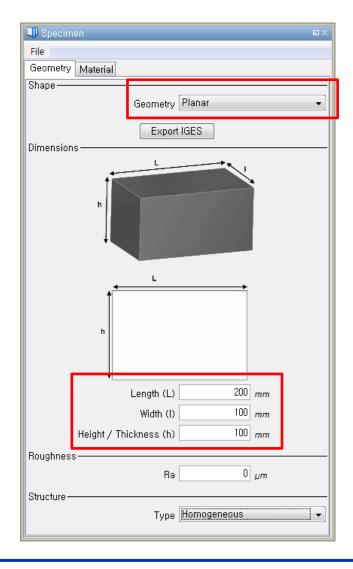
❖UT 시작 및 Specimen 생성

Beam computation 모듈 활성화





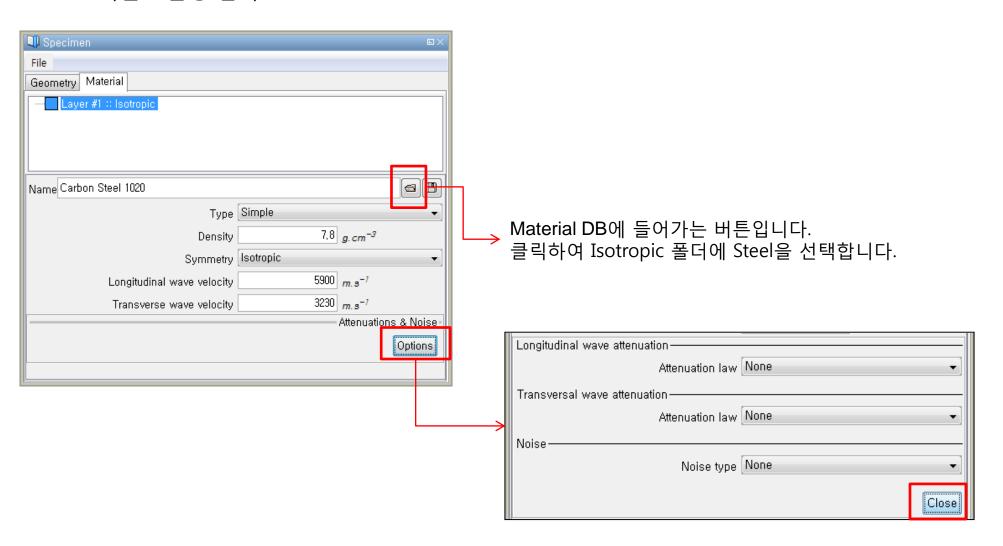
■ 시편 - 형상 선정 및 치수 입력





♦Specimen 물성 설정

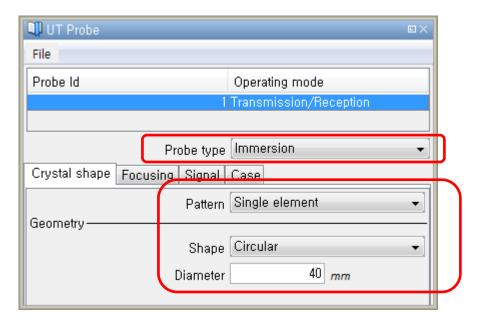
■ 시편 – 물성 입력

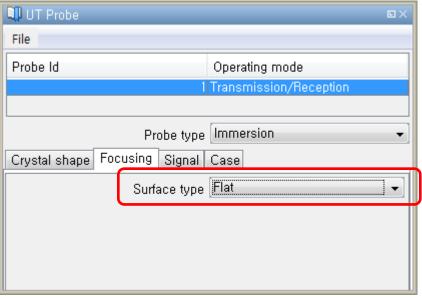




❖Probe 수정(1/2)

■ Probe 수정

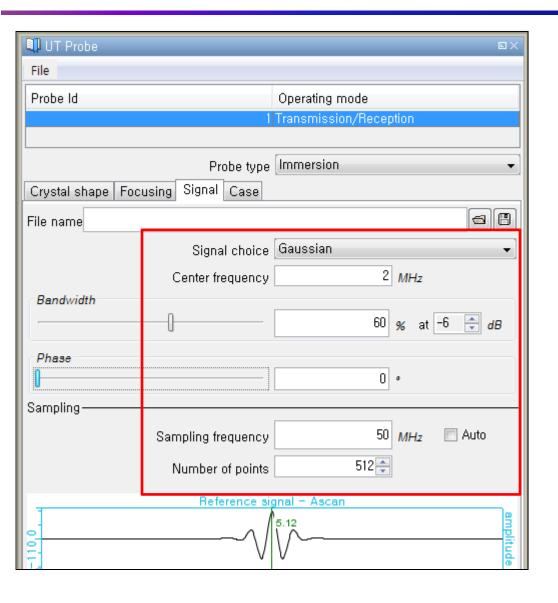


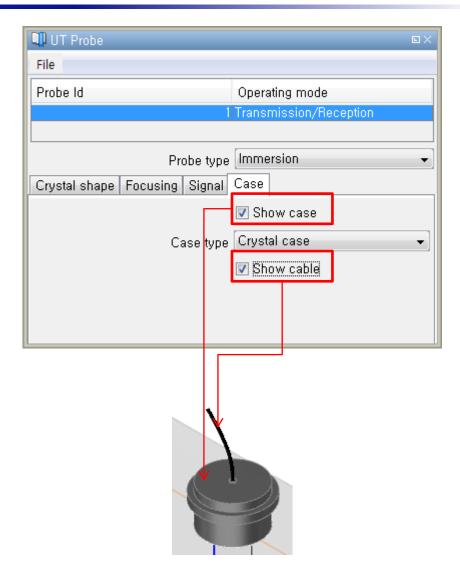


Focusing – Flat은 Non-focused probe를 의미합니다.



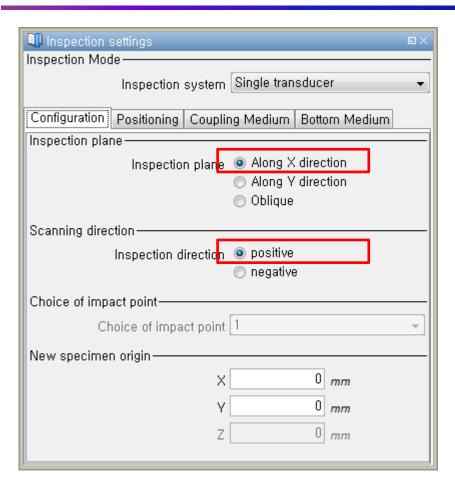
❖Probe 수정(2/2)







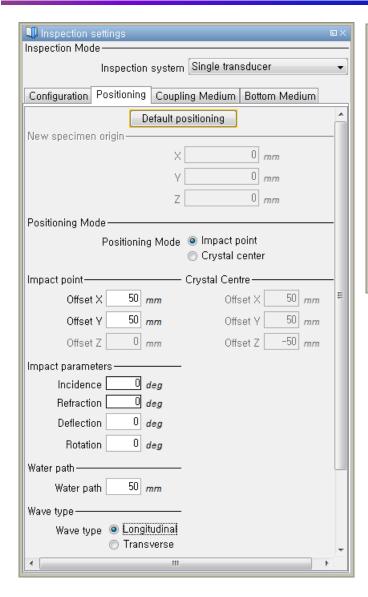
❖Inspection 설정(1/2)

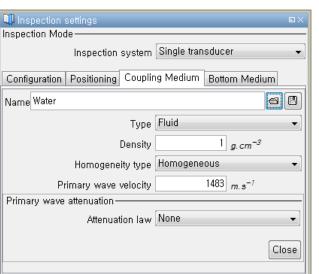


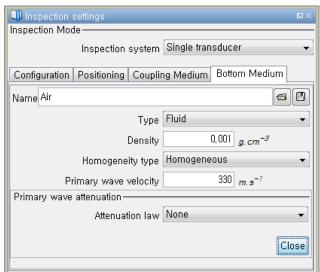


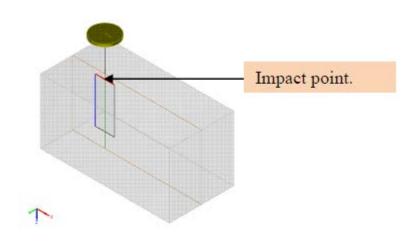
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❖Inspection 설정(2/2)



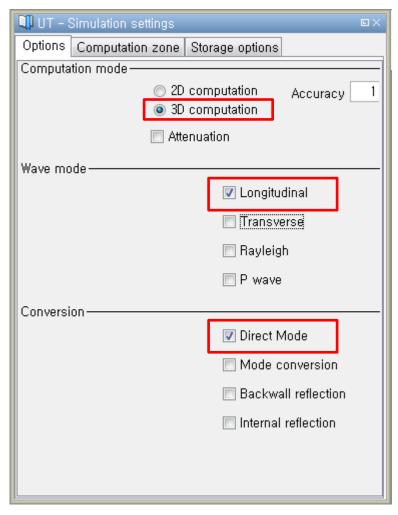


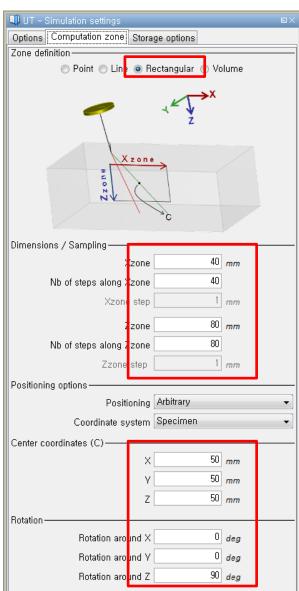


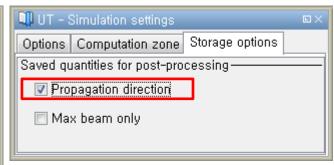


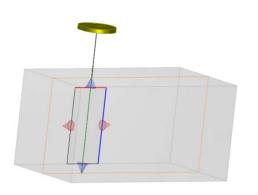


♦Simulation setting



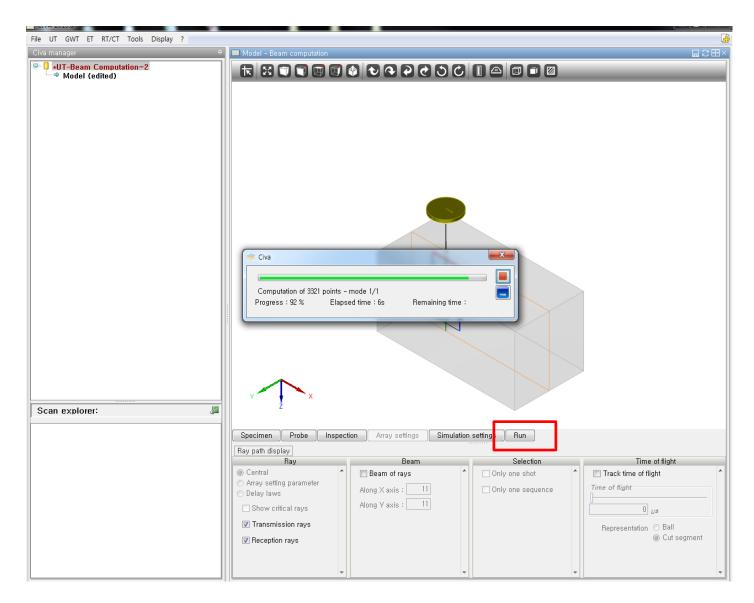






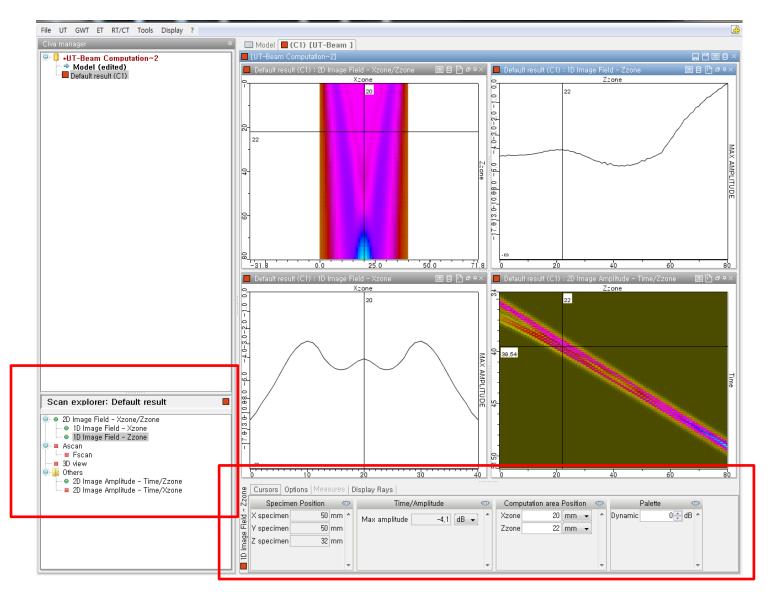


❖Solving 진행(Run)





❖Post-processing





❖Example – Immersion Testing

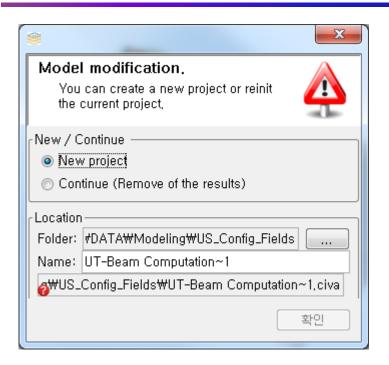
1. L0 inspection with a non-focused transducer

2. L0 inspection with a spherically focused transducer

3. L60 inspection



◇입력 조건 및 기타 내용 변경



해석이 완료된 상태에서 입력 조건 등을 변경하에 되면 왼쪽과 같은 창이 나오면서, 파일 저장을 물어봅니다.

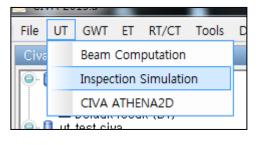
1.새로운 이름으로 저장 2.해석 결과 삭제 후 변경된 조건으로 해석

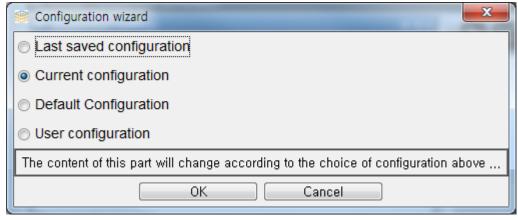
위의 두 가지 선택사항이 제공됩니다.

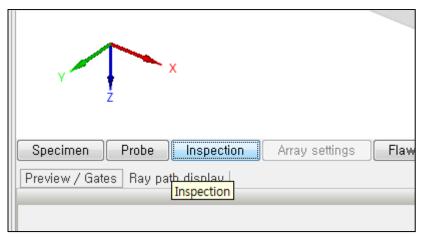


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❖Inspection simulation으로 변경 및 Flaw 생성



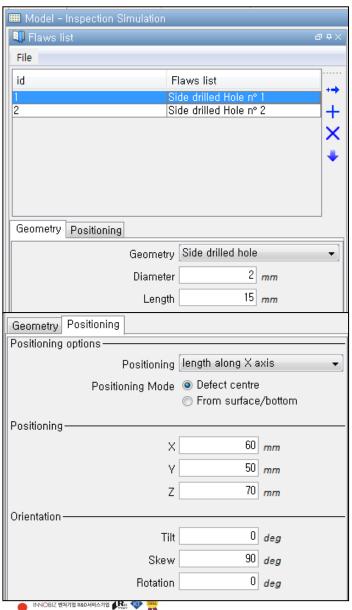


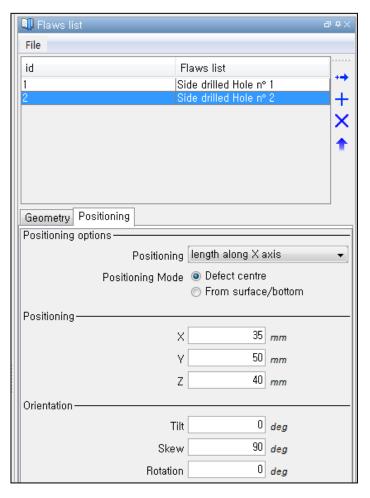


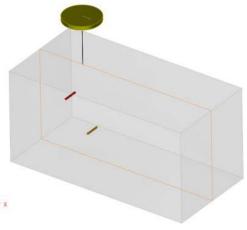
계산이 완료된 후 UT – Inspection Simulation을 선택하면 Configuration wizard가 활성화 된다.



❖Flaw 생성



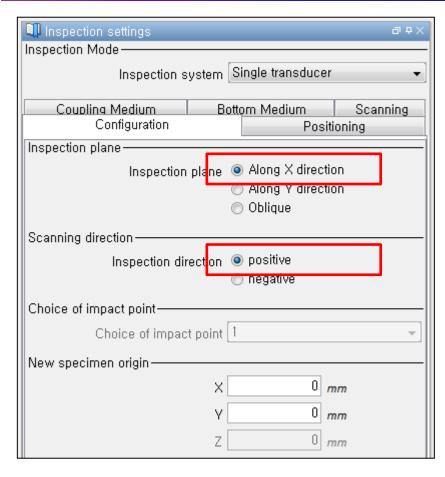


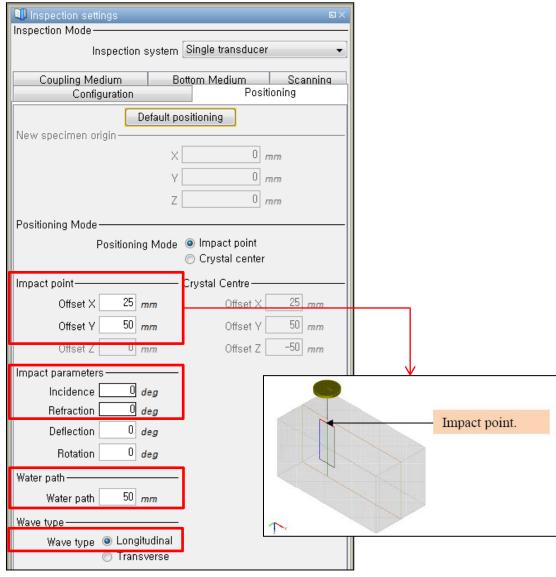


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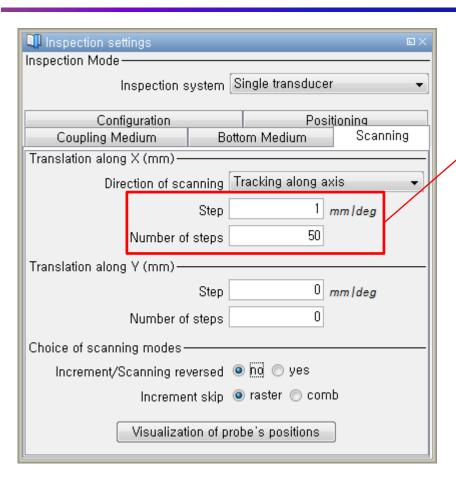
❖Inspection 설정(1/2)







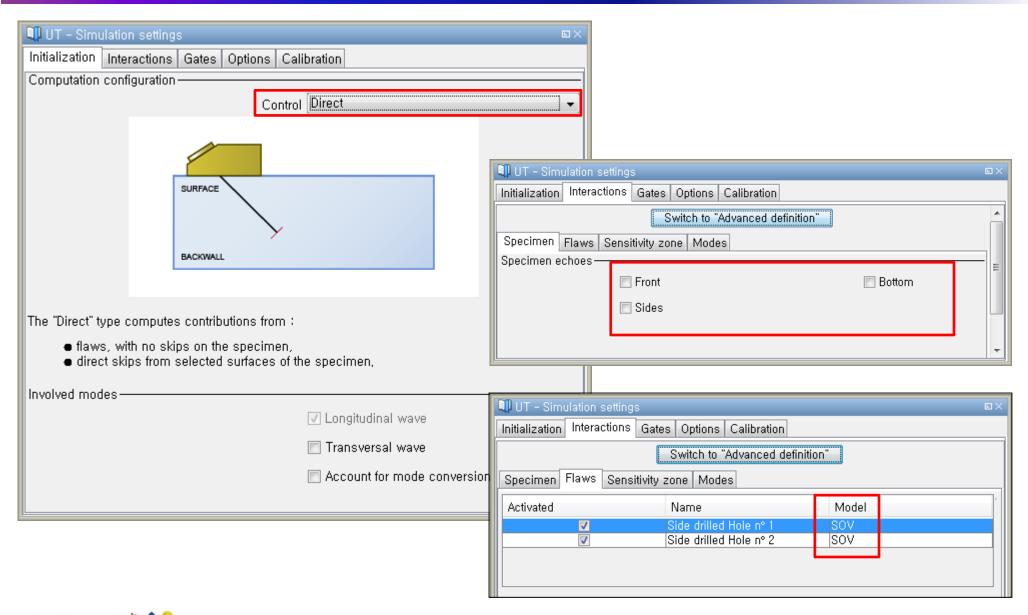
♦Inspection 설정(2/2)



1mm/deg의 step value로 50회 진행

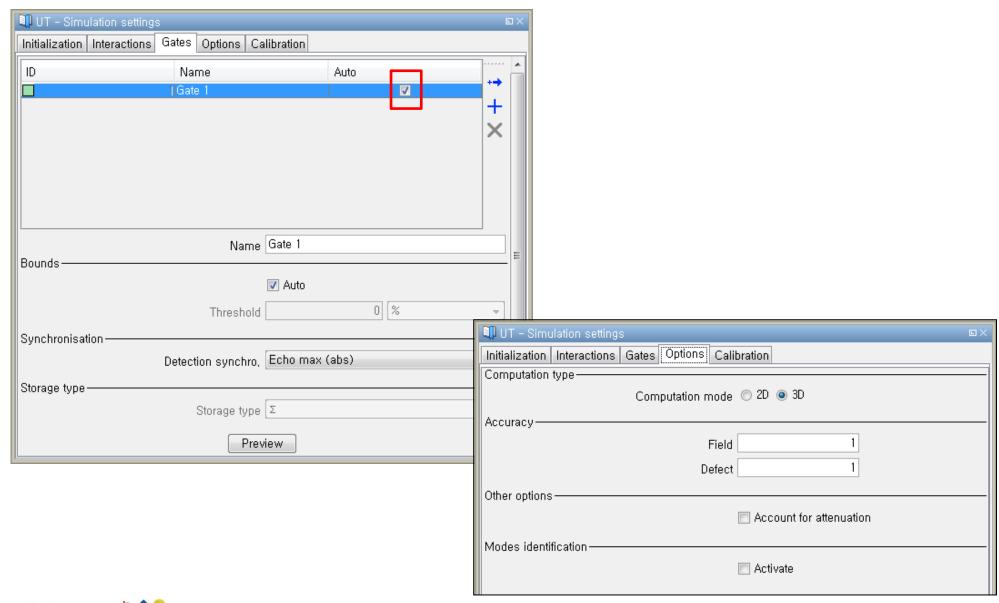


♦Simulation setting 변경



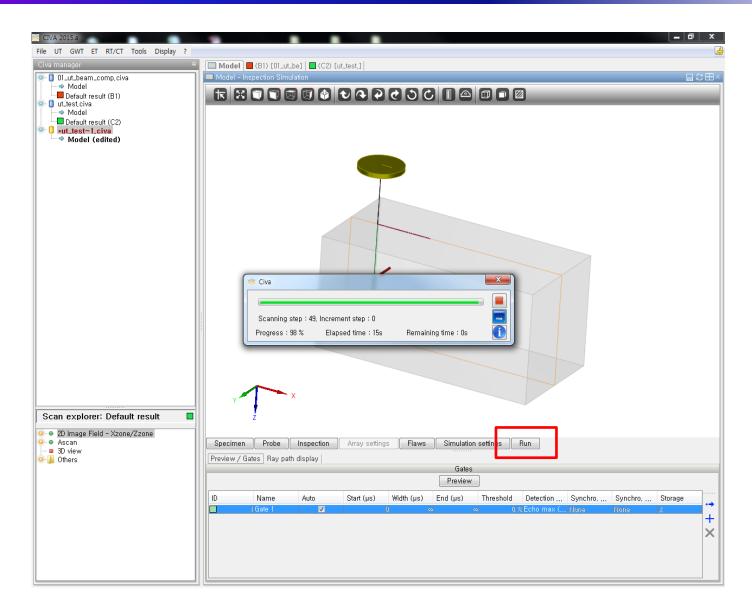


❖Simulation settings



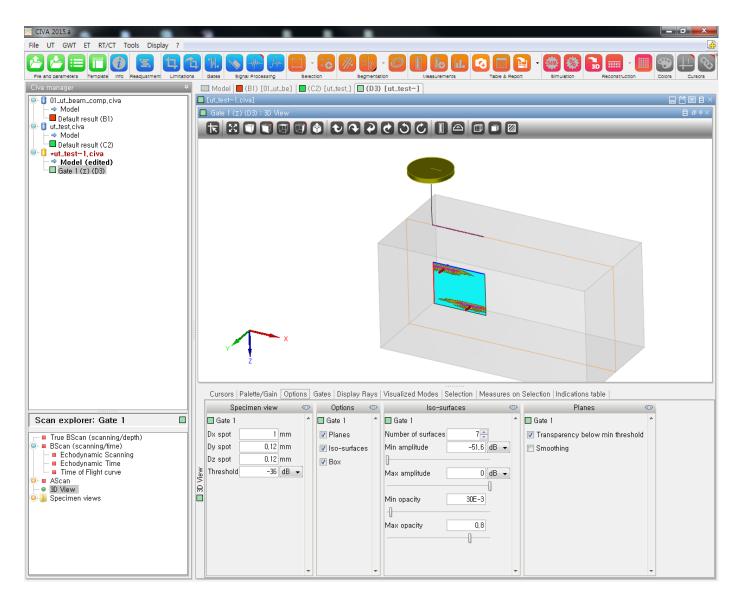


❖해석 진행(Run)





❖결과 확인(1/2)

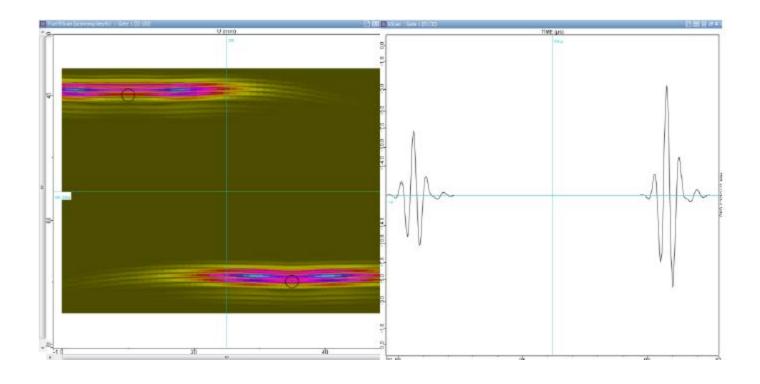




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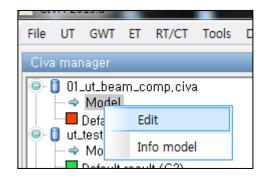
❖결과 확인(2/2)

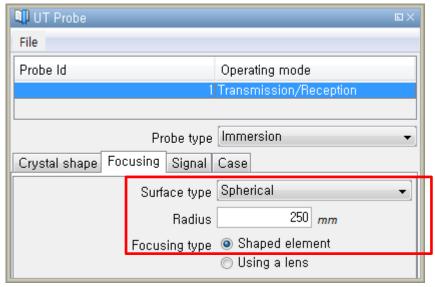
■ B-scan, A-Scan 형상





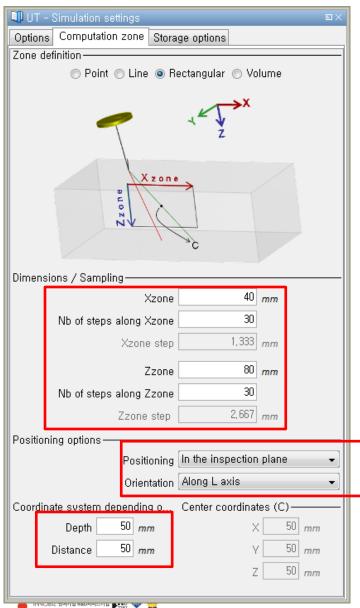
❖Inspection with a focused transducer





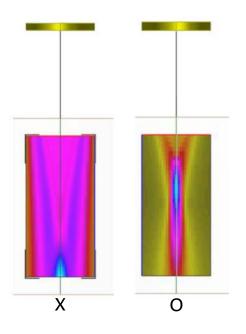


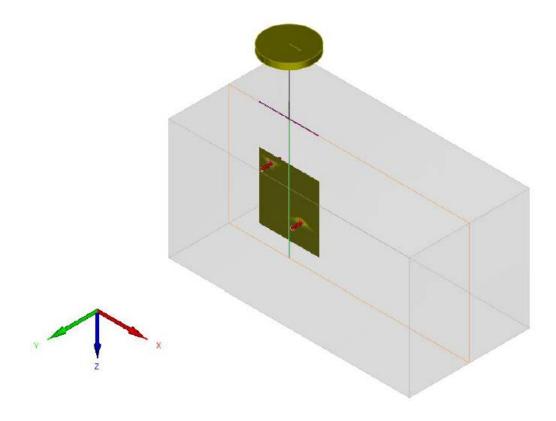
❖Simulation Settings



❖Result 비교

■ Focusing surface 여부에 따른 결과 차이







❖Example – Immersion Testing

1. L0 inspection with a non-focused transducer

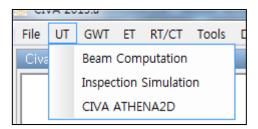
2. L0 inspection with a spherically focused transducer

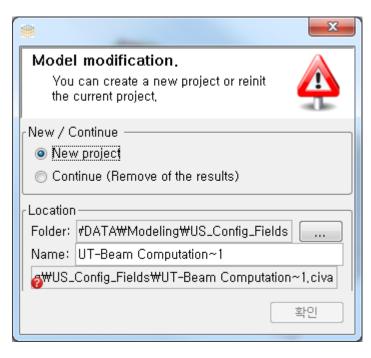
3. L60 inspection

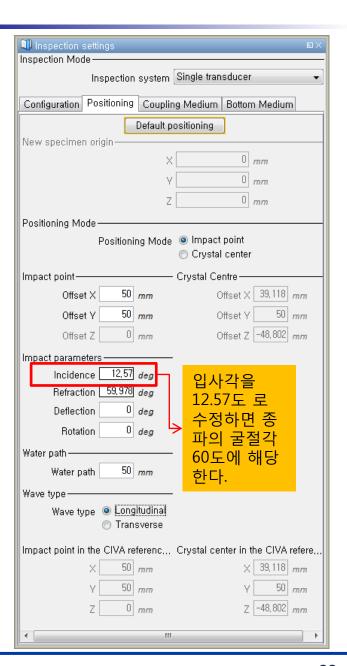


❖L60도 해석 준비 및 Inspection 설정

- Beam Computation 모드
- Create a new file 및 save 파일
- Inspection setting Positioning 선택

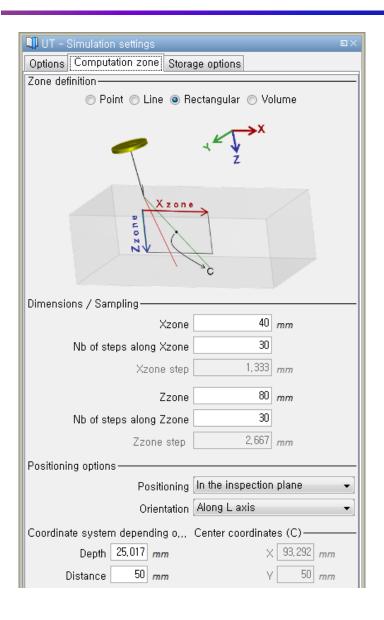


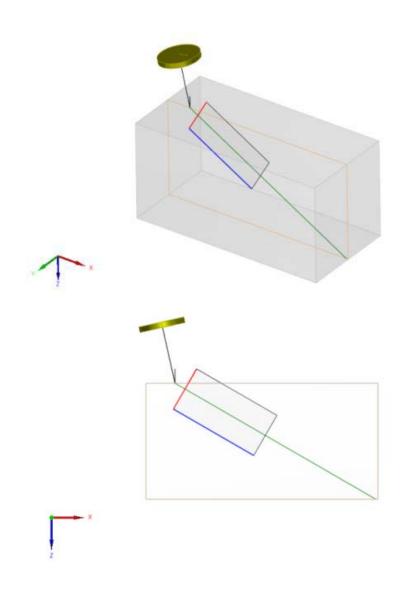






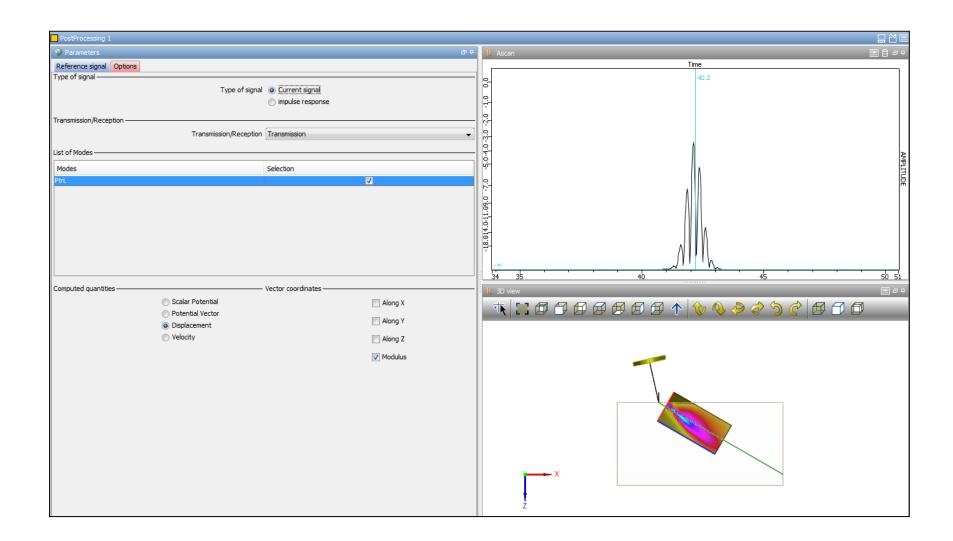
❖Simulation 설정(해석 영역 선정)





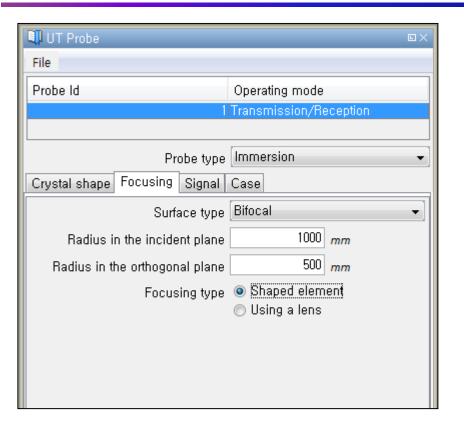


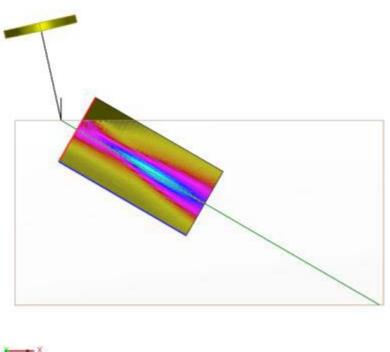
♦해석 및 결과 확인





♦Bifocal 계산 설정 및 결과







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Thank You!

대한민국 전기 : 기계

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